MOSFET – Power, N-Channel, Logic Level, DPAK/IPAK

20 A, 60 V

Designed for low voltage, high speed switching applications in power supplies, converters and power motor controls and bridge circuits.

Features

- AEC Q101 Qualified NTDV20N06L
- These Devices are Pb-Free and are RoHS Compliant

Typical Applications

- Power Supplies
- Converters
- Power Motor Controls
- Bridge Circuits

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	V _{DSS}	60	Vdc
Drain-to-Gate Voltage (R _{GS} = 10 MΩ)	V_{DGR}	60	Vdc
Gate–to–Source Voltage – Continuous – Non–repetitive (t _p ≤ 10 ms)	V _{GS} V _{GS}	±15 +20	Vdc
$ \begin{array}{c c} \text{Drain Current} & -\text{Continuous} @ T_A = 25^{\circ}\text{C} \\ -\text{Continuous} @ T_A = 100^{\circ}\text{C} \\ -\text{Single Pulse} (t_p \leq 10 \ \mu\text{s}) \end{array} $	I _D	20 10 60	Adc Apk
Total Power Dissipation @ T _A = 25°C Derate above 25°C Total Power Dissipation @ T _A = 25°C (Note 1) Total Power Dissipation @ T _A = 25°C (Note 2)	P _D	60 0.40 1.88 1.36	W W/°C W W
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to +175	°C
Single Pulse Drain-to-Source Avalanche Energy – Starting T_J = 25°C (V_{DD} = 25 Vdc, V_{GS} = 5.0 Vdc, L = 1.0 mH, I_L (pk) = 16 A, V_{DS} = 60 Vdc)	E _{AS}	128	mJ
Thermal Resistance - Junction-to-Case - Junction-to-Ambient (Note 1) - Junction-to-Ambient (Note 2)	$egin{array}{c} R_{ heta JC} \ R_{ heta JA} \ R_{ heta JA} \end{array}$	2.5 80 110	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8 in from case for 10 seconds	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

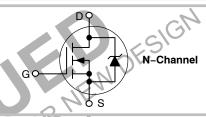
- 1. When surface mounted to an FR4 board using 1 in pad size, (Cu Area 1.127 in²).
- When surface mounted to an FR4 board using recommended pad size, (Cu Area 0.412 in²).



ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX
60 V	39 mΩ@5.0 V	20 A (Note 1)



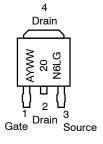


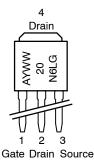


DPAK CASE 369C STYLE 2

IPAK CASE 369D STYLE 2

MARKING DIAGRAMS & PIN ASSIGNMENTS





A = Assembly Location*

Y = Year
WW = Work Week
20N6L = Device Code
G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

^{*} The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise noted)

C	haracteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Vo (V _{GS} = 0 Vdc, I _D = 250 μAdc) Temperature Coefficient (Positiv	V _{(BR)DSS}	60 -	71.3 71.2	- -	Vdc mV/°C	
Zero Gate Voltage Drain Curren ($V_{DS} = 60 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc}$) ($V_{DS} = 60 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc}$,	I _{DSS}	- -		1.0 10	μAdc	
Gate-Body Leakage Current (V	I _{GSS}	1	-	±100	nAdc	
N CHARACTERISTICS (Note 3)					
Gate Threshold Voltage (Note 3 $(V_{DS} = V_{GS}, I_D = 250 \mu Adc)$ Threshold Temperature Coeffici		V _{GS(th)}	1.0	1.6 4.6	2.0	Vdc mV/°C
Static Drain-to-Source On-Res $(V_{GS} = 5.0 \text{ Vdc}, I_D = 10 \text{ Adc})$	sistance (Note 3)	R _{DS(on)}	-	39	48	mΩ
Static Drain-to-Source On-Res ($V_{GS} = 5.0 \text{ Vdc}$, $I_D = 20 \text{ Adc}$) ($V_{GS} = 5.0 \text{ Vdc}$, $I_D = 10 \text{ Adc}$,	V _{DS(on)}	-	0.81 0.72	1.66	Vdc	
Forward Transconductance (No	g _F s	-	17.5	-	mhos	
YNAMIC CHARACTERISTICS				111		
Input Capacitance		C _{iss}	2-1/1/	707	990	pF
Output Capacitance	$(V_{DS} = 25 \text{ Vdc}, V_{GS} = 0 \text{ Vdc},$ f = 1.0 MHz)	C _{oss}	~ ~	224	320	
Transfer Capacitance		C _{rss}	7.5	72	105	
WITCHING CHARACTERISTIC	S (Note 4)	a FD	U2 V	110		
Turn-On Delay Time		t _{d(on)}	Mr	9.6	20	ns
Rise Time	$(V_{DD} = 30 \text{ Vdc}, I_D = 20 \text{ Adc}, V_{GS} = 5.0 \text{ Vdc},$	(h)) <u>, </u>	98	200	
Turn-Off Delay Time	$R_G = 9.1 \Omega$) (Note 3)	t _{d(off)}	_	25	50	
Fall Time	CO. C.	C tr	-	62	120	
Gate Charge	(V _{DS} = 48 Vdc, I _D = 20 Adc,	Q _T	-	16.6	32	nC
46	$V_{DS} = 48 \text{ VdC}, I_D = 20 \text{ AdC},$ $V_{GS} = 5.0 \text{ VdC}) \text{ (Note 3)}$	Q ₁	-	5.5	-	
		Q ₂	-	8.5	-	
OURCE-DRAIN DIODE CHARA						
Forward On-Voltage	$(I_S = 20 \text{ Adc}, V_{GS} = 0 \text{ Vdc}) \text{ (Note 3)}$ $(I_S = 20 \text{ Adc}, V_{GS} = 0 \text{ Vdc}, T_J = 150^{\circ}\text{C})$	V _{SD}	1 1	0.97 0.85	1.2 -	Vdc
Reverse Recovery Time	20041	t _{rr}	_	42	_	ns
, GV	(I _S = 20 Adc, V _{GS} = 0 Vdc, dI _S /dt = 100 A/μs) (Note 3)	t _a	_	30	_	
HIS	2	t _b	-	12	-	
Reverse Recovery Stored Char	ge	Q_{RR}	-	0.066	-	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

ORDERING INFORMATION

Device	Package	Shipping [†]
NTD20N06LG	DPAK (Pb-Free)	75 Units / Rail
NTD20N06L-1G	IPAK (Straight Lead) (Pb-Free)	75 Units / Rail
NTD20N06LT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTDV20N06LT4G	DPAK (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{3.} Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

^{4.} Switching characteristics are independent of operating junction temperatures.

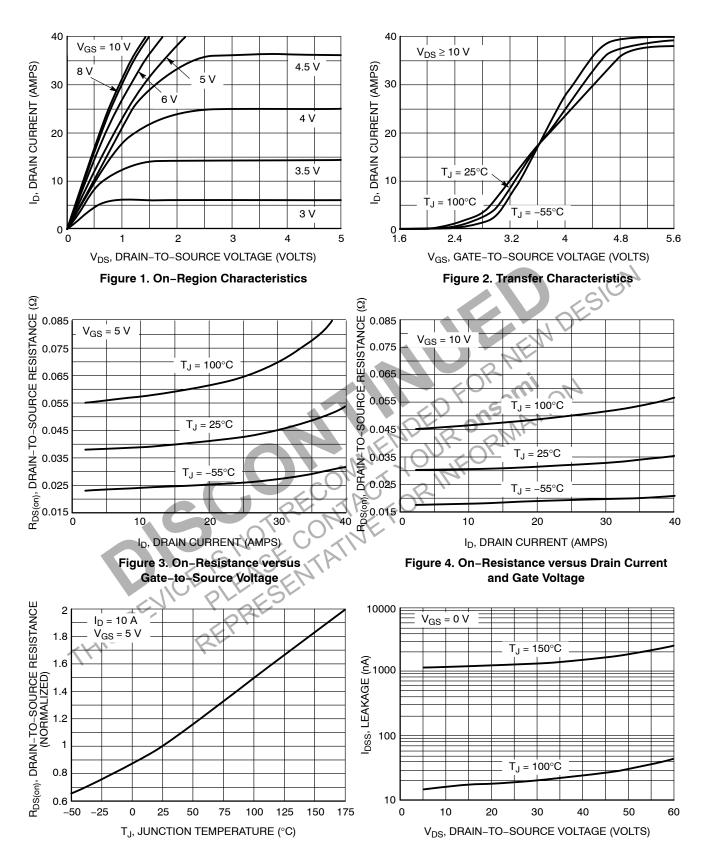


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage

POWER MOSFET SWITCHING

Switching behavior is most easily modeled and predicted by recognizing that the power MOSFET is charge controlled. The lengths of various switching intervals (Δt) are determined by how fast the FET input capacitance can be charged by current from the generator.

The published capacitance data is difficult to use for calculating rise and fall because drain–gate capacitance varies greatly with applied voltage. Accordingly, gate charge data is used. In most cases, a satisfactory estimate of average input current $(I_{G(AV)})$ can be made from a rudimentary analysis of the drive circuit so that

$$t = Q/I_{G(AV)}$$

During the rise and fall time interval when switching a resistive load, V_{GS} remains virtually constant at a level known as the plateau voltage, V_{SGP} Therefore, rise and fall times may be approximated by the following:

$$t_r = Q_2 \times R_G/(V_{GG} - V_{GSP})$$

$$t_f = Q_2 \times R_G/V_{GSP}$$

where

 V_{GG} = the gate drive voltage, which varies from zero to V_{GG} R_{G} = the gate drive resistance

and Q₂ and V_{GSP} are read from the gate charge curve.

During the turn-on and turn-off delay times, gate current is not constant. The simplest calculation uses appropriate values from the capacitance curves in a standard equation for voltage change in an RC network. The equations are:

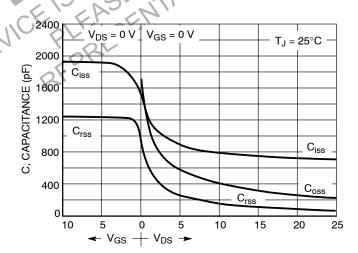
$$t_{d(on)} = R_G C_{iss} In \left[V_{GG} / (V_{GG} - V_{GSP}) \right]$$

$$t_{d(off)} = R_G C_{iss} In (V_{GG}/V_{GSP})$$

The capacitance (C_{iss}) is read from the capacitance curve at a voltage corresponding to the off-state condition when calculating $t_{d(on)}$ and is read at a voltage corresponding to the on-state when calculating $t_{d(off)}$.

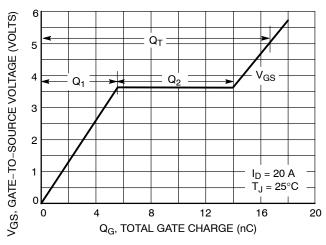
At high switching speeds, parasitic circuit elements complicate the analysis. The inductance of the MOSFET source lead, inside the package and in the circuit wiring which is common to both the drain and gate current paths, produces a voltage at the source which reduces the gate drive current. The voltage is determined by Ldi/dt, but since di/dt is a function of drain current, the mathematical solution is complex. The MOSFET output capacitance also complicates the mathematics. And finally, MOSFETs have finite internal gate resistance which effectively adds to the resistance of the driving source, but the internal resistance is difficult to measure and, consequently, is not specified.

The resistive switching time variation versus gate resistance (Figure 9) shows how typical switching performance is affected by the parasitic circuit elements. If the parasitics were not present, the slope of the curves would maintain a value of unity regardless of the switching speed. The circuit used to obtain the data is constructed to minimize common inductance in the drain and gate circuit loops and is believed readily achievable with board mounted components. Most power electronic loads are inductive; the data in the figure is taken with a resistive load, which approximates an optimally snubbed inductive load. Power MOSFETs may be safely operated into an inductive load; however, snubbing reduces switching losses.



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation



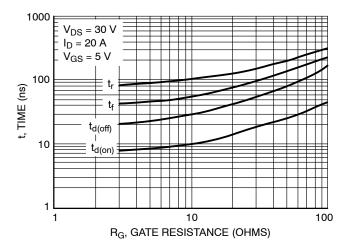


Figure 8. Gate-To-Source and Drain-To-Source
Voltage versus Total Charge

Figure 9. Resistive Switching Time Variation versus Gate Resistance
CTERISTICS

DRAIN-TO-SOURCE DIODE CHARACTERISTICS

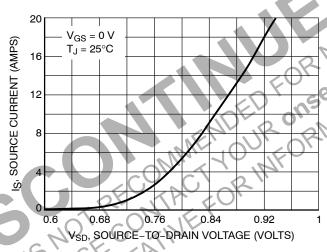


Figure 10. Diode Forward Voltage versus Current

SAFE OPERATING AREA

The Forward Biased Safe Operating Area curves define the maximum simultaneous drain-to-source voltage and drain current that a transistor can handle safely when it is forward biased. Curves are based upon maximum peak junction temperature and a case temperature (T_C) of 25°C. Peak repetitive pulsed power limits are determined by using the thermal response data in conjunction with the procedures discussed in AN569, "Transient Thermal Resistance – General Data and Its Use."

Switching between the off-state and the on-state may traverse any load line provided neither rated peak current (I_{DM}) nor rated voltage (V_{DSS}) is exceeded and the transition time ($t_p t_f$) do not exceed 10 μ s. In addition the total power averaged over a complete switching cycle must not exceed ($T_{J(MAX)} - T_C$)/($R_{\theta JC}$).

A Power MOSFET designated E-FET can be safely used in switching circuits with unclamped inductive loads. For

reliable operation, the stored energy from circuit inductance dissipated in the transistor while in avalanche must be less than the rated limit and adjusted for operating conditions differing from those specified. Although industry practice is to rate in terms of energy, avalanche energy capability is not a constant. The energy rating decreases non–linearly with an increase of peak current in avalanche and peak junction temperature.

Although many E–FETs can withstand the stress of drain–to–source avalanche at currents up to rated pulsed current (I_{DM}), the energy rating is specified at rated continuous current (I_{D}), in accordance with industry custom. The energy rating must be derated for temperature as shown in the accompanying graph (Figure 12). Maximum energy at currents below rated continuous I_{D} can safely be assumed to equal the values indicated.

SAFE OPERATING AREA

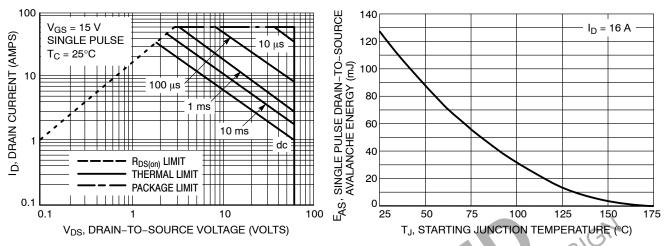


Figure 11. Maximum Rated Forward Biased **Safe Operating Area**

Figure 12. Maximum Avalanche Energy versus **Starting Junction Temperature**

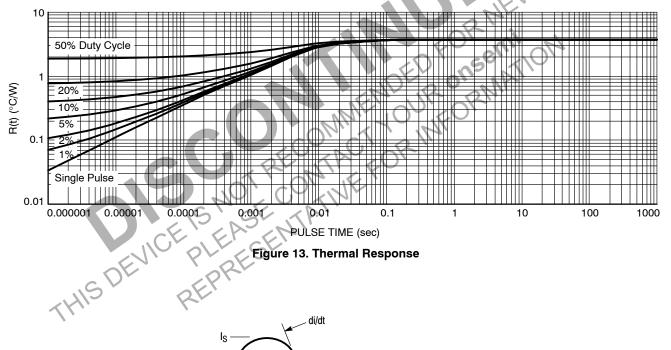


Figure 13. Thermal Response

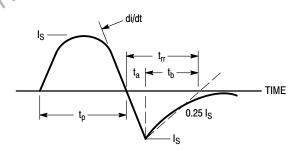


Figure 14. Diode Reverse Recovery Waveform



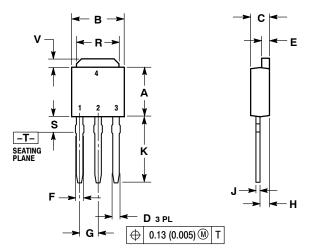


DPAK INSERTION MOUNT

CASE 369 ISSUE O

DATE 02 JAN 2000





- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INC	HES	MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.250	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.033	0.040	0.84	1.01
F	0.037	0.047	0.94	1.19
G	0.090	BSC	2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.175	0.215	4.45	5.46
S	0.050	0.090	1.27	2.28
V	0.030	0.050	0.77	1 27

STYLE 1:		STYLE 2:		STYLE 3:		STYLE 4:		STYLE 5:		STYLE 6:	
PIN 1.	BASE	PIN 1.	GATE	PIN 1.	ANODE	PIN 1.	CATHODE	PIN 1.	GATE	PIN 1.	MT1
2.	COLLECTOR	2.	DRAIN	2.	CATHODE	2.	ANODE	2.	ANODE	2.	MT2
3.	EMITTER	3.	SOURCE	3.	ANODE	3.	GATE	3.	CATHODE	3.	GATE
4.	COLLECTOR	4.	DRAIN	4.	CATHODE	4.	ANODE	4.	ANODE	4.	MT2

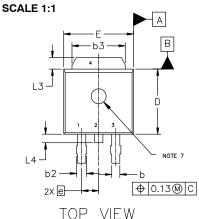
DOCUMENT NUMBER:	98ASB42319B	Electronic versions are uncontrolled except when accessed directly from the Document Reprinted versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK INSERTION MOUNT		PAGE 1 OF 1	

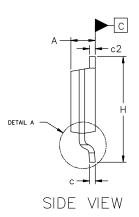
onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. onsemi does not convey any license under its patent rights nor the rights of others.



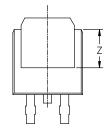
DPAK3 6.10x6.54x2.28, 2.29P CASE 369C **ISSUE J**

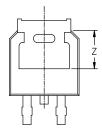
DATE 12 AUG 2025

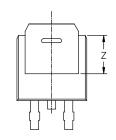


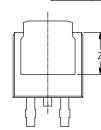


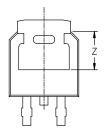
MILLIMETERS					
DIM	MIN NOM MAX				
А	2.18	2.28	2.38		
A1	0.00		0.13		
b	0.63	0.76	0.89		
b2	0.72	0.93	1.14		
b3	4.57	5.02	5.46		
С	0.46	0.54	0.61		
c2	0.46	0.54	0.61		
D	5.97	6.10	6.22		
E	6.35	6.54	6.73		
е	:	2.29 BSC			
Н	9.40	9.91	10.41		
L	1.40	1.59	1.78		
L1	2.90 REF				
L2	0.51 BSC				
L3	0.89		1.27		
L4			1.01		
Z	3.93				











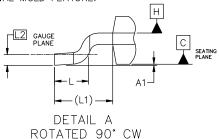
BOTTOM VIEW

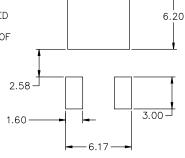
ALTERNATE CONSTRUCTIONS

NOTES:

- DIMENSIONING AND TOLERANCING ASME Y14.5M, 2018.

- CONTROLLING DIMENSION: MILLIMETERS.
 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3, AND Z.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR
 BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DATUMS A AND B ARE DETERMINED AT DATUM PLANE H. OPTIONAL MOLD FEATURE.





-5.80

RECOMMENDED MOUNTING FOOTPRINT*

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ONSEMI SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

DOCUMENT NUMBER:	98AON10527D	Electronic versions are uncontrolled except when accessed directly from the Document Repositon Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK3 6.10x6.54x2.28, 2.2	9P	PAGE 1 OF 2	

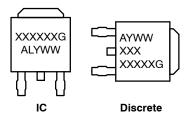
onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. onsemi does not convey any license under its patent rights nor the rights of others.

DPAK3 6.10x6.54x2.28, 2.29P

CASE 369C ISSUE J

DATE 12 AUG 2025

GENERIC MARKING DIAGRAM*



XXXXXX = Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
WW = Work Week
G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

STYLE 1:	STYLE 2:	STYLE 3:	STYLE 4:	STYLE 5:
PIN 1. BASE	PIN 1. GATE	PIN 1. ANODE	PIN 1. CATHODE	PIN 1. GATE
2. COLLECTOR	2. DRAIN	2. CATHODE	2. ANODE	ANODE
EMITTER	SOURCE	ANODE	3. GATE	CATHODE
COLLECTOR	4. DRAIN	CATHODE	4. ANODE	ANODE

STYLE 6: PIN 1. MT1 2. MT2 3. GATE	STYLE 7: PIN 1. GATE 2. COLLECTOR 3. EMITTER	STYLE 8: PIN 1. N/C 2. CATHODE 3. ANODE	PIN 1. ANODE 2. CATHODE 3. RESISTOR ADJUST	STYLE 10: PIN 1. CATHODE 2. ANODE 3. CATHODE
4. MT2	COLLECTOR	CATHODE	4. CATHODE	ANODE

DOCUMENT NUMBER:	98AON10527D	Electronic versions are uncontrolled except when accessed directly from the Document Repos Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK3 6.10x6.54x2.28, 2.2	9P	PAGE 2 OF 2	

onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. onsemi does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI., and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems. or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales